



MEG02-005

serial no. 10/786,807

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

SUBJECT: Serial #: 10/786,807
 File Date: Feb. 25, 2004
 Inventor: Hui-Mei Chen, C.K.Chou, J.Y. Lee, H.T.Liu
 Examiner: Au, Bach
 Art Unit: 2822
 Title: METHOD FOR IMPROVING SEMICONDUCTOR
 WAFER TEST ACCURACY

DECLARATION UNDER 37 CFR 1.131

Honorable Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

I, Hui_mei Chen, C. K. Chou, J. Y. Lee, H. T. Liu, hereby state:

1. I am a co-inventor of Claims 15-33 of the above-identified patent application.
2. Prior to March 6, 2003, we conceived of the idea for the method(s) of testing semiconductor wafers as described and claimed in our application, and a copy of the invention disclosure describing our invention entered the United States of America before March 6, 2003. The invention disclosure including drawings shows our invention as claimed in Claims 15, 17, 27, and 30, and is attached as Exhibit A (18 pages). Each of the dates blanked out from Exhibit A is prior to March 6, 2003. Each of the dates is also after January 1, 2002, the date that Taiwan joined the WTO.

3. George O. Saile & Associates faxed to us a draft copy of the patent application on November 26, 2002. This draft shows that the contact is gold. A copy of the draft is attached as Exhibit B.
4. We added the inventive cleaning process to our product line. A Microsoft® Excel file shows the ion milling cleaning process run on March 24, 2003, attached as Exhibit C.
5. These exhibits show conception prior to the effective date of the reference plus due diligence from prior to the reference date of March 6, 2003 to actual reduction to practice on March 24, 2003.

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Hui-Mei Chen. May 24, 2006
Hui-Mei Chen Date

Chian Kong Chou May 16, 2006
C. K. Chou Date

Jin-Yuan Lee May 16, 2006
J. Y. Lee Date

Hsiao-Tsuap Liu, May 16, 2006
H. T. Liu Date